

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	644244	(determin\$5 or detect\$5 or measur\$5 or inspect\$5 or monitor\$5 or evaluat\$5 or calculat\$5) near5 (sample or object or wafer or surface) and @ad<="19980918"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:14
L2	15304	compar\$5 with ((reference or baseline or predetermin\$5) near4 image)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 09:17
L3	128615	(determin\$5 or detect\$5 or measur\$5 or inspect\$5 or monitor\$5 or evaluat\$5 or calculat\$5) near8 (reflect\$5 near2 (light or beam))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 09:17
L4	2545	((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or monitor\$5 or evaluat\$5 or calculat\$5) near4 (flaw or defect\$2 or particle or crack)) with (compar\$5 near10 image)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 09:17
L5	34	L1 and L2 and L3 and L4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 09:17
L6	1071	((chang\$5 or control\$5 or adjust\$5 or modif\$8 or reduce or decrease or increase or amplif\$5) near10 amplitude) with ((reflect\$5 or diffract\$5) near2 light)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 09:58
L7	0	L4 and L6 and @ad<="19980918"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 09:58
L8	202203	((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or monitor\$5 or evaluat\$5 or calculat\$5) near4 (flaw or defect\$2 or particle or crack))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 09:59
L9	35	L6 and L8 and @ad<="19980918"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 09:59

## EAST Search History

L10	341	(amplitude near3 ((reflect\$5 or diffract\$5) near2 light)) near8 (adjust\$5 or control\$5 or decrease\$5 or change\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:00
L11	5	L4 and L10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:00
L12	1195496	(determine\$5 or detect\$5 or measure\$5 or inspect\$5 or monitor\$5 or evaluate\$5 or calculate\$5) near5 (sample or object or wafer or surface)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:09
L13	27830	(image or imaging) with (compare\$5 with (reference or baseline or predetermined\$5))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:01
L14	2883	((reduce or reducing or adjust or adjusting or control or controlling) near3 amplitude) near10 (light beam)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:01
L15	21	L12 and L13 and L14	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:01
L16	4942	((reduce or reducing or adjust or adjusting or control or controlling or change or changing) near3 amplitude) near10 (light or beam)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:04
L17	57	L12 and L13 and L16	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:04
L18	60532	((determine\$5 or detect\$5 or measure\$5 or inspect\$5 or monitor\$5 or evaluate\$5 or calculate\$5) near5 (defect or particle or abnormal\$5)) with (sample or object or wafer or surface)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:05

## EAST Search History

L19	503	((reduce or reducing or adjust or adjusting or control or controlling or change or changing) near3 amplitude) near10 ((reflect\$5 or diffract\$5) near3 (light or beam))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:05
L20	20	L19 and L18	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:05
L21	8	L12 and L19 and L13	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:06
L22	11	L19 and L13	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:06
L23	748	((reduc\$5 or adjust\$5 or control\$5 or chang\$5 or decreas\$5) near3 amplitude) near10 ((reflect\$5 or diffract\$5) near3 (light or beam))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:06
L24	358	L12 and L23	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:06
L25	11	L24 and L13	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:07
L26	53	polarizer with ((reduc\$5 or adjust\$5 or lower or weak\$5 or change or changing) near3 (amplitude or magnitud\$2)) with (light or signal or beam)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 13:01
L28	21	12 and 26	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:27
L29	1	28 and (objective near2 lens\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:46

## EAST Search History

L30	11	28 and (image or imaging)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 10:46
L31	2341	(356/364,365,366,367,368,369). CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/10 12:46
L32	4013	(356/237.1,237.2,237.3,237.4,237. 5,237.6).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/10 12:47
L33	528	(250/559.42,559.48).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/10 12:47
L34	547	(382/149).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/10 12:47
L35	7190	31 or 32 or 33 or 34	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 12:47
L36	27	35 and 12 and 19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 12:48
L37	1	((polarizer with ((reduc\$5 or adjust\$5 or lower or weak\$5 or change or changing) near3 (amplitude or magnitud\$2)) with (light or signal or beam)) and ((determin\$5 or detect\$5 or measur\$5 or inspect\$5 or monitor\$5 or evaluat\$5 or calculat\$5) near5 (sample or object or wafer or surface))).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/10 13:02